

CMOS linear image sensor



S16596-4096-11

High IR sensitivity, smooth spectral response

The S16596-4096-11 is a high sensitivity CMOS linear image sensor using a photosensitive area with vertically long pixels (7 \times 200 μ m). Other features include smoothly varying spectral response characteristics. Sensitivity in near IR region (λ =830 nm) is realized nearly double compared to the previous type (S13496-11). The S16596-4096-11 operates from a single 5 V supply making it suitable for use in low cost spectrometers.

Features

- → Pixel size: 7 × 200 μm
- Number of effective pixels: 4008,20 pixels on each end: optical black
- Effective photosensitive area length: 28.056 mm
- ightharpoonup High sensitivity: 900 V/(lx·s)
- ➡ Simultaneous charge integration for all pixels
- Variable integration time function (electronic shutter function)
- **■** 5 V single power supply operation
- Built-in timing generator allows operation with only start and clock pulse inputs
- Video data rate: 10 MHz max.

- Applications

- Raman spectrometers
- Position detection
- **■** Image reading
- **SD-OCT**

(spectral domain-optical coherence tomography)

Structure

Parameter	Specification	Unit
Number of pixels	4096	-
Pixel size	7 × 200	μm
Photosensitive area length	28.672	mm
Number of effective pixels	4008	
Package	LCP (liquid crystal polymer)	-
Window material*1	Borosilicate glass with AR coating*2	

^{*1:} Window-less type (S16596-4096N-11) is available upon request.

- Absolute maximum ratings

Parameter	Symbol	Condition	Value	Unit
Supply voltage	Vdd	Ta=25 °C	-0.3 to +6	V
Clock pulse voltage	V(CLK)	Ta=25 °C	-0.3 to +6	V
Start pulse voltage	V(ST)	Ta=25 °C	-0.3 to +6	V
Operating temperature	Topr	No dew condensation*3	-40 to +85	°C
Storage temperature	Tstg	No dew condensation*3	-40 to +85	°C

^{*3:} When there is a temperature difference between a product and the surrounding area in high humidity environment, dew condensation may occur on the product surface. Dew condensation on the product may cause deterioration in characteristics and reliability.

^{*2:} The average reflectance is 1% or less in 400 to 1050 nm.

Note: Exceeding the absolute maximum ratings even momentarily may cause a drop in product quality. Always be sure to use the product within the absolute maximum ratings.

➡ Recommended terminal voltage (Ta=25 °C)

Parame	Parameter		Min.	Тур.	Max.	Unit
Supply voltage		Vdd	4.75	5	5.25	V
Clock pulse veltage	High level	WCLK)	3	Vdd	Vdd + 0.25	V
Clock pulse voltage	Low level	V(CLK)	0	-	0.3	V
Ctart mules voltage	High level	V/(CT)	3	Vdd	Vdd + 0.25	V
Start pulse voltage	Low level	V(ST)	0	-	0.3	V

Input terminal capacitance (Ta=25 °C, Vdd=5 V) Input terminal capacitance (Ta=25 °C, Vdd=5 V)

Parameter	Symbol	Min.	Тур.	Max.	Unit
Clock pulse input terminal capacitance	C(CLK)	-	5	-	pF
Start pulse input terminal capacitance	C(ST)	-	5	-	pF

■ Electrical characteristics [Ta=25 °C, Vdd=5 V, V(CLK)=V(ST)=5 V]

Parameter	Symbol	Min.	Тур.	Max.	Unit
Clock pulse frequency	f(CLK)	200 k	-	10 M	Hz
Data rate	DR	-	f(CLK)	-	Hz
Output impedance	Zo	70	-	260	Ω
Current consumption*4 *5	Ic	20	40	60	mA

^{*4:} f(CLK)=10 MHz

■ Electrical and optical characteristics [Ta=25 °C, Vdd=5 V, V(CLK)=V(ST)=5 V, f(CLK)=10 MHz]

Parameter	Symbol	Min.	Тур.	Max.	Unit
Spectral response range	λ		400 to 1050		nm
Peak sensitivity wavelength	λр	-	750	-	nm
Photosensitivity*6	Sw	-	900	-	V/(lx·s)
Conversion efficiency*7	CE	-	20	-	μV/e⁻
Dark output voltage*8	Vd	0	0.25	4	mV
Saturation output voltage*9 *10	Vsat	1.5	2.0	2.5	V
Readout noise	Nread	0.1	0.4	1.2	mV rms
Dynamic range 1*11	Drange1	-	5000	-	times
Dynamic range 2*12	Drange2	-	8000	-	times
Output offset voltage	Voffset	0.3	0.6	0.9	V
Photoresponse nonuniformity*6 *13	PRNU	-	±2	±10	%
Image lag*14	Lag	-	-	0.1	%

^{*6:} Measured with a tungsten lamp of 2856 K

- *11: Drange1 = Vsat/Nread
- *12: Drange2 = Vsat/Vd

Integration time=10 ms

Dark output voltage is proportional to the integration time and so the shorter the integration time, the wider the dynamic range.

*13: Photoresponse nonuniformity (PRNU) is the output nonuniformity that occurs when the entire photosensitive area is uniformly illuminated by light which is 50% of the saturation exposure level. PRNU is measured using 4002 pixels excluding 3 pixels each at both ends, and is defined as follows:

PRNU = $\Delta X/X \times 100$ (%)

X: average output of all pixels, ΔX : difference between X and maximum output or minimum output

*14: Signal components of the preceding line data that still remain even after the data is read out in a saturation output state. Image lag increases when the output exceeds the saturation output voltage.



^{*5:} Current consumption increases as the clock pulse frequency increases. The current consumption is 10 mA typ. at f(CLK)=200 kHz.

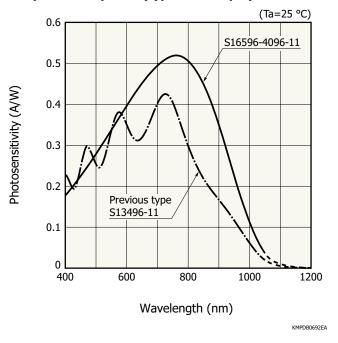
^{*7:} Output voltage generated per one electron

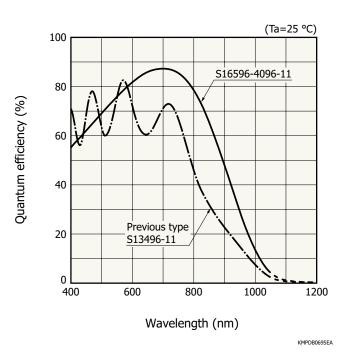
^{*8:} Integration time=10 ms

^{*9:} Difference from Voffset

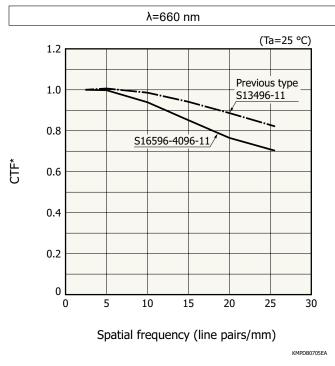
^{*10:} CDS (correlated double sampling) is done inside the image sensor in order to reduce noise. The final output is the difference between the output when the photosensitive area is put in the reset state, and the light output integrated in the photosensitive area. If used in an over-saturated state, the light output component may get mixed into the output when the photosensitive area is put in the reset state, causing the final output to decrease.

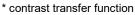
Spectral response (typical example)

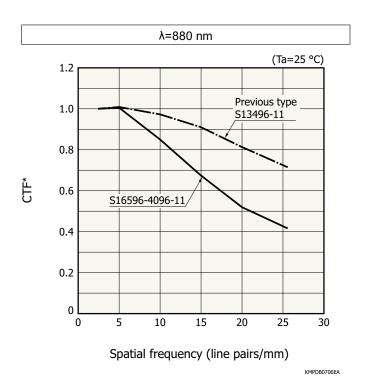




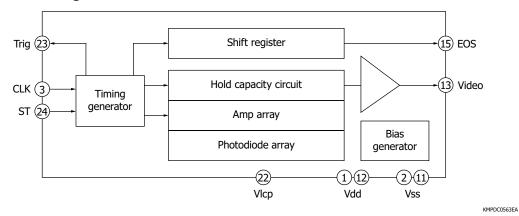
Resolution characteristics (typical example)





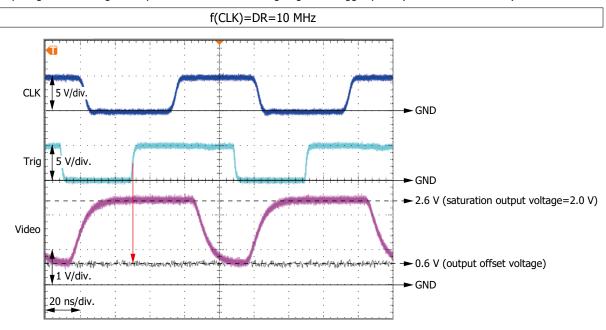


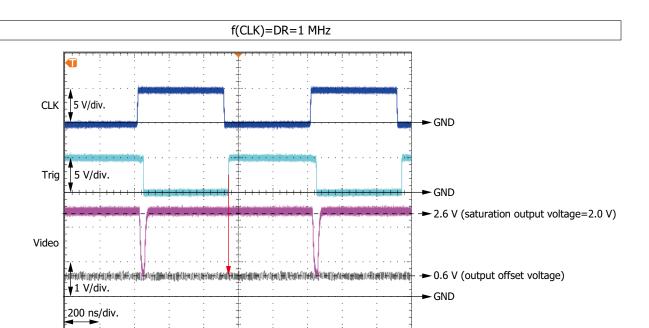
Block diagram



Output waveform of one pixel

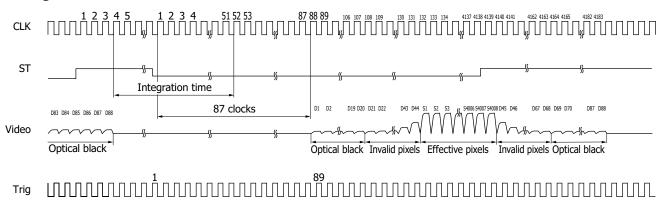
The timing for acquiring the Video signal is synchronized with the rising edge of a trigger pulse (See red arrow below.).

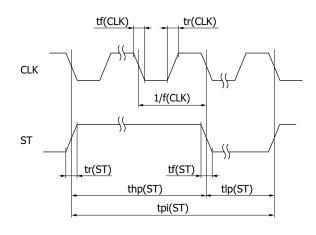




- Timing chart

EOS





KMPDC1037EA

Parameter	Symbol	Min.	Тур.	Max.	Unit
Start pulse width interval*15	tpi(ST)	106/f(CLK)	-	-	S
Start pulse high period*15 *16	thp(ST)	6/f(CLK)	-	-	S
Start pulse low period	tlp(ST)	100/f(CLK)	-	-	S
Start pulse rise and fall times	tr(ST), tf(ST)	0	10	30	ns
Clock pulse duty	-	45	50	55	%
Clock pulse rise and fall times	tr(CLK), tf(CLK)	0	10	30	ns

^{*15:} Dark output increases if the start pulse period or the start pulse high period is lengthened.

The shift register starts operation at the rising edge of CLK immediately after ST goes low.

The integration time can be changed by changing the ratio of the high and low periods of ST.

If the first Trig pulse after ST goes low is counted as the first pulse, the Video signal is acquired at the rising edge of the 89th Trig pulse.

Note: After power-on, do not float the ST and CLK input terminals. Instead, set them to high level or low level. Immediately after power-on, the signal in the sensor becomes undefined. Do not use invalid data from the first scan. Instead, use valid data from the second scan onwards.



^{*16:} The integration time equals the high period of ST plus 48 CLK cycles.

Operation example

■ When outputting from all 4096 pixels

This example assumes that the clock pulse frequency is maximized (data rate is also maximized), the time of one scan is minimized, and the integration time is maximized

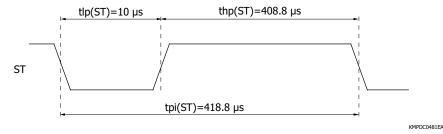
Clock pulse frequency = Data rate = 10 MHz

Start pulse cycle = $4188/f(CLK) = 4188/10 \text{ MHz} = 418.8 \,\mu\text{s}$

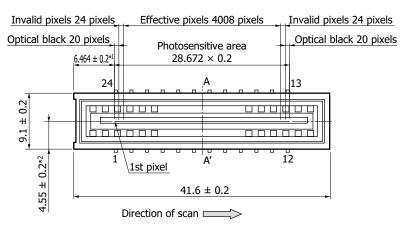
High period of start pulse = Start pulse cycle - Start pulse's low period min.

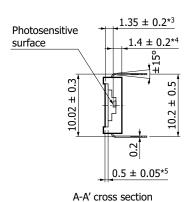
= $4188/f(CLK) - 100/f(CLK) = 4188/10 MHz - 100/10 MHz = 408.8 \mu s$

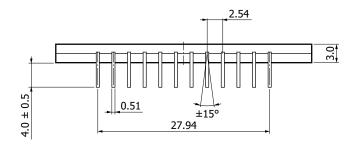
Integration time is equal to the high period of start pulse + 48 cycles of clock pulses, so it will be 408.8 + 4.8 = 413.6 µs.



Dimensional outline (unit: mm)







Tolerance unless otherwise noted: ± 0.1

- *1: Distance from package edge to photosensitive area edge
- *2: Distance from package edge to photosensitive area center
- *3: Distance from glass surface to photosensitive surface
- *4: Distance from package bottom to photosensitive surface
- *5: Glass thickness

KMPDA0582EA

Pin connections

Pin no.	Symbol	I/O	Description	Pin no.	Symbol	I/O	Description
1	Vdd	I	Supply voltage	13	Video	0	Video signal*17
2	Vss	-	GND	14	NC	-	No connection
3	CLK	I	Clock pulse	15	EOS	0	End of scan
4	NC	-	No connection	16	NC	-	No connection
5	NC	-	No connection	17	NC	-	No connection
6	NC	-	No connection	18	NC	-	No connection
7	NC	-	No connection	19	NC	-	No connection
8	NC	-	No connection	20	NC	-	No connection
9	NC	-	No connection	21	NC	-	No connection
10	NC	-	No connection	22	Vlcp	-	Bias voltage for negative voltage circuit*18
11	Vss	-	GND	23	Trig	0	Trigger pulse for video signal acquisition*19
12	Vdd	I	Supply voltage	24	ST	I	Start pulse

^{*17:} Connect a buffer amplifier for impedance conversion to the video output terminal so as to minimize the current flow. As the buffer amplifier, use a high input impedance operational amplifier with JFET or CMOS input.

Note: Leave the "NC" terminals open and do not connect them to GND.

Recommended soldering conditions

Parameter	Specification	Note
Soldering temperature	260 °C max. (5 seconds or less)	

Note: When you set soldering conditions, check that problems do not occur in the product by testing out the conditions in advance.

Precautions

(1) Electrostatic countermeasures

This device has a built-in protection circuit against static electrical charges. However, to prevent destroying the device with electrostatic charges, take countermeasures such as grounding yourself, the workbench and tools to prevent static discharges. Also protect this device from surge voltages which might be caused by peripheral equipment.

(2) Light input window

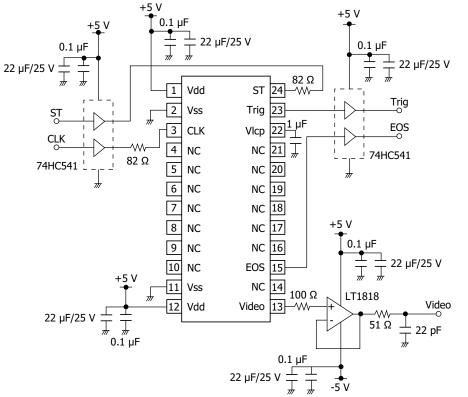
If dust or dirt gets on the light input window, it will show up as black blemishes on the image. When cleaning, avoid rubbing the window surface with dry cloth or dry cotton swab, since doing so may generate static electricity. Use soft cloth, paper or a cotton swab moistened with alcohol to wipe dust and dirt off the window surface. Then blow compressed air onto the window surface so that no spot or stain remains.



^{*18:} Approximately -1.5 V generated by the negative voltage circuit inside the chip is output to the terminal. To maintain the voltage, insert a capacitor around 1 µF between Vlcp and GND.

^{*19:} We recommend capturing video signal using the trigger pulse output from Trig.

Application circuit example



KMPDC0564EA

- Related information

www.hamamatsu.com/sp/ssd/doc_en.html

- Precautions
- · Disclaimer
- · Image sensors
- Technical note
- · CMOS linear image sensors

Driver circuit for CMOS linear image sensors C16605 [sold separately]

The driver circuit for CMOS linear image sensor S16596-4096-11 is available (sold separately). It can be used for spectrometers, etc. combining with the CMOS linear image

Contact us for detailed information.

Features

- **■** Built-in 16-bit A/D converter
- **■** Interface to computer: USB 2.0
- Power supply: USB bus power operation



Information described in this material is current as of April 2024.

Product specifications are subject to change without prior notice due to improvements or other reasons. This document has been carefully prepared and the information contained is believed to be accurate. In rare cases, however, there may be inaccuracies such as text errors. Before using these products, always contact us for the delivery specification sheet to check the latest specifications.

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